

**FEATURES**
**3-axis sensing**
**Small, low-profile package**
**4 mm × 4 mm × 1.45 mm LFCSP**
**Low power - 350  $\mu$ A (typical)**
**Single-supply operation**
**1.8 V to 3.6 V**
**10,000 g shock survival**
**Excellent temperature stability**
**BW adjustment with a single capacitor per axis**
**RoHS/WEEE lead-free compliant**
**APPLICATIONS**
**Cost-sensitive, low power, motion- and tilt-sensing applications**
**Mobile devices**
**Gaming systems**
**Disk drive protection**
**Image stabilization**
**Sports and health devices**
**GENERAL DESCRIPTION**

The ADXL335 is a small, thin, low power, complete 3-axis accelerometer with signal conditioned voltage outputs. The product measures acceleration with a minimum full-scale range of  $\pm 3 g$ . It can measure the static acceleration of gravity in tilt-sensing applications, as well as dynamic acceleration resulting from motion, shock, or vibration.

The user selects the bandwidth of the accelerometer using the  $C_x$ ,  $C_y$ , and  $C_z$  capacitors at the  $X_{OUT}$ ,  $Y_{OUT}$ , and  $Z_{OUT}$  pins. Bandwidths can be selected to suit the application, with a range of 0.5 Hz to 1600 Hz for X and Y axes, and a range of 0.5 Hz to 550 Hz for the Z axis.

The ADXL335 is available in a small, low profile, 4 mm × 4 mm × 1.45 mm, 16-lead, plastic lead frame chip scale package (LFCSP\_LQ).

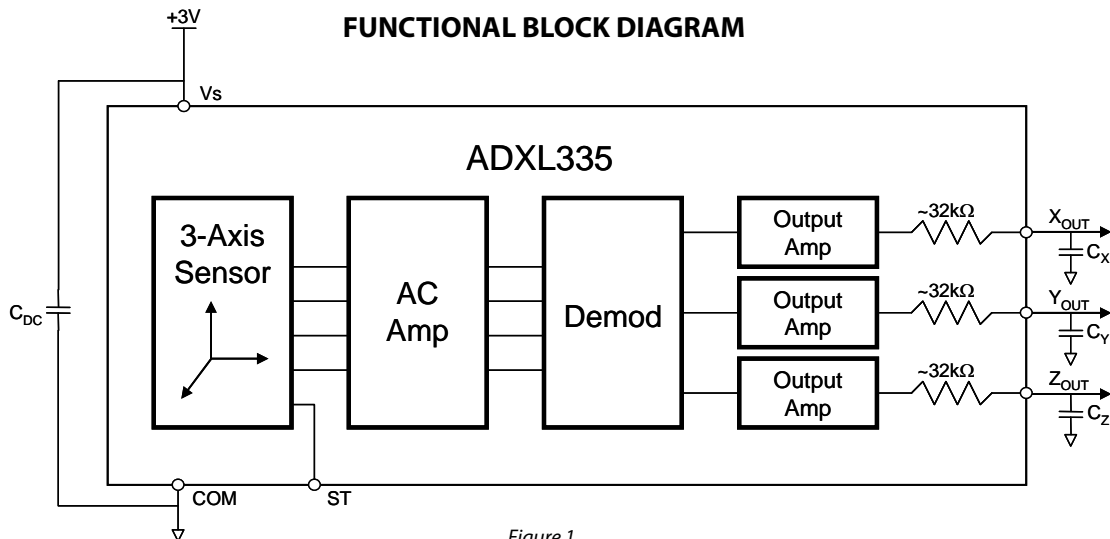


Figure 1.

**Rev. PrA**

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**REVISION HISTORY**

## SPECIFICATIONS

$T_A = 25^\circ\text{C}$ ,  $V_S = 3\text{ V}$ ,  $C_X = C_Y = C_Z = 0.1\ \mu\text{F}$ , acceleration = 0 g, unless otherwise noted. All minimum and maximum specifications are guaranteed. Typical specifications are not guaranteed.

Table 1.

Parameter	Conditions	Min	Typ	Max	Unit
<b>SENSOR INPUT</b>					
Measurement Range	Each axis	$\pm 3$	$\pm 3.6$		g
Nonlinearity	% of full scale		$\pm 0.3$		%
Package Alignment Error			$\pm 1$		Degrees
Interaxis Alignment Error			$\pm 0.1$		Degrees
Cross Axis Sensitivity <sup>1</sup>			$\pm 1$		%
<b>SENSITIVITY (RATIOMETRIC)<sup>2</sup></b>					
Sensitivity at $X_{\text{OUT}}$ , $Y_{\text{OUT}}$ , $Z_{\text{OUT}}$	$V_S = 3\text{ V}$	270	300	330	mV/g
Sensitivity Change Due to Temperature <sup>3</sup>	$V_S = 3\text{ V}$		$\pm 0.01$		%/ $^\circ\text{C}$
<b>ZERO g BIAS LEVEL (RATIOMETRIC)</b>					
0 g Voltage at $X_{\text{OUT}}$ , $Y_{\text{OUT}}$	$V_S = 3\text{ V}$	1.35	1.5	1.65	V
0 g Voltage at $Z_{\text{OUT}}$	$V_S = 3\text{ V}$	1.2	1.5	1.8	V
0 g Offset vs. Temperature			$\pm 1$		mg/ $^\circ\text{C}$
<b>NOISE PERFORMANCE</b>					
Noise Density $X_{\text{OUT}}$ , $Y_{\text{OUT}}$			150		$\mu\text{g}/\sqrt{\text{Hz}}$ rms
Noise Density $Z_{\text{OUT}}$			300		$\mu\text{g}/\sqrt{\text{Hz}}$ rms
<b>FREQUENCY RESPONSE<sup>4</sup></b>					
Bandwidth $X_{\text{OUT}}$ , $Y_{\text{OUT}}$ <sup>5</sup>	No external filter		1600		Hz
Bandwidth $Z_{\text{OUT}}$ <sup>5</sup>	No external filter		550		Hz
$R_{\text{FILT}}$ Tolerance			$32 \pm 15\%$		k $\Omega$
Sensor Resonant Frequency			5.5		kHz
<b>SELF TEST<sup>6</sup></b>					
Logic Input Low			+0.6		V
Logic Input High			+2.4		V
ST Actuation Current			+60		$\mu\text{A}$
Output Change at $X_{\text{OUT}}$	Self test 0 to 1		-300		mV
Output Change at $Y_{\text{OUT}}$	Self test 0 to 1		+300		mV
Output Change at $Z_{\text{OUT}}$	Self test 0 to 1		+550		mV
<b>OUTPUT AMPLIFIER</b>					
Output Swing Low	No load		0.1		V
Output Swing High	No load		2.8		V
<b>POWER SUPPLY</b>					
Operating Voltage Range		1.8		3.6	V
Supply Current	$V_S = 3\text{ V}$		350		$\mu\text{A}$
Turn-On Time <sup>7</sup>	No external filter		1		ms
<b>TEMPERATURE</b>					
Operating Temperature Range		-40		+85	$^\circ\text{C}$

<sup>1</sup> Defined as coupling between any two axes.

<sup>2</sup> Sensitivity is essentially ratiometric to  $V_S$ .

<sup>3</sup> Defined as the output change from ambient-to-maximum temperature or ambient-to-minimum temperature.

<sup>4</sup> Actual frequency response controlled by user-supplied external filter capacitors ( $C_X$ ,  $C_Y$ ,  $C_Z$ ).

<sup>5</sup> Bandwidth with external capacitors =  $1/(2 \times \pi \times 32\text{ k}\Omega \times C)$ . For  $C_X$ ,  $C_Y = 0.003\ \mu\text{F}$ , bandwidth = 1.6 kHz. For  $C_Z = 0.01\ \mu\text{F}$ , bandwidth = 500 Hz. For  $C_X$ ,  $C_Y$ ,  $C_Z = 10\ \mu\text{F}$ , bandwidth = 0.5 Hz.

<sup>6</sup> Self-test response changes cubically with  $V_S$ .

<sup>7</sup> Turn-on time is dependent on  $C_X$ ,  $C_Y$ ,  $C_Z$  and is approximately  $160 \times C_X$  or  $C_Y$  or  $C_Z + 1\text{ ms}$ , where  $C_X$ ,  $C_Y$ ,  $C_Z$  are in  $\mu\text{F}$ .

## ABSOLUTE MAXIMUM RATINGS

Table 2.

Parameter	Rating
Acceleration (Any Axis, Unpowered)	10,000 g
Acceleration (Any Axis, Powered)	10,000 g
$V_s$	-0.3 V to +3.6 V
All Other Pins	(COM - 0.3 V) to ( $V_s + 0.3 V$ )
Output Short-Circuit Duration (Any Pin to Common)	Indefinite
Temperature Range (Powered)	-55°C to +125°C
Temperature Range (Storage)	-65°C to +150°C

Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

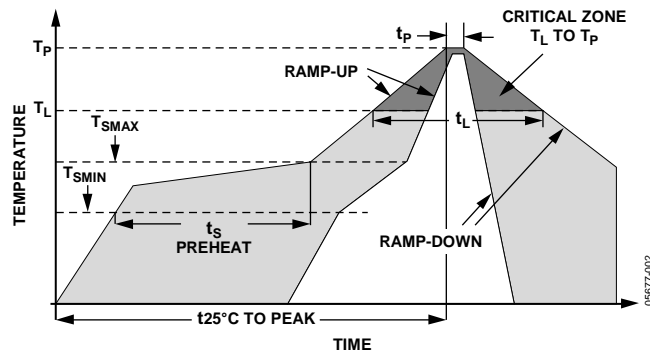


Figure 2. Recommended Soldering Profile

Table 3. Recommended Soldering Profile

Profile Feature	Sn63/Pb37	Pb-Free
Average Ramp Rate ( $T_L$ to $T_P$ )	3°C/s max	3°C/s max
Preheat		
Minimum Temperature ( $T_{SMIN}$ )	100°C	150°C
Maximum Temperature ( $T_{SMAX}$ )	150°C	200°C
Time ( $T_{SMIN}$ to $T_{SMAX}$ ), $t_s$	60 s to 120 s	60 s to 180 s
$T_{SMAX}$ to $T_L$		
Ramp-Up Rate	3°C/s max	3°C/s max
Time Maintained Above Liquidous ( $T_L$ )		
Liquidous Temperature ( $T_L$ )	183°C	217°C
Time ( $t_L$ )	60 s to 150 s	60 s to 150 s
Peak Temperature ( $T_P$ )	240°C + 0°C/-5°C	260°C + 0°C/-5°C
Time within 5°C of Actual Peak Temperature ( $t_p$ )	10 s to 30 s	20 s to 40 s
Ramp-Down Rate	6°C/s max	6°C/s max
Time 25°C to Peak Temperature	6 minutes max	8 minutes max

### ESD CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although this product features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.



### PIN CONFIGURATION AND FUNCTION DESCRIPTIONS

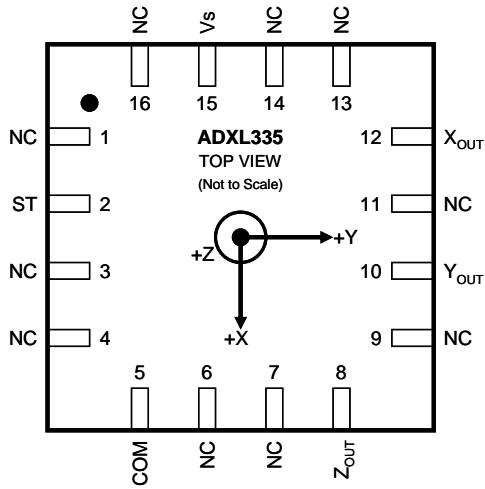


Figure 3. Pin Configuration

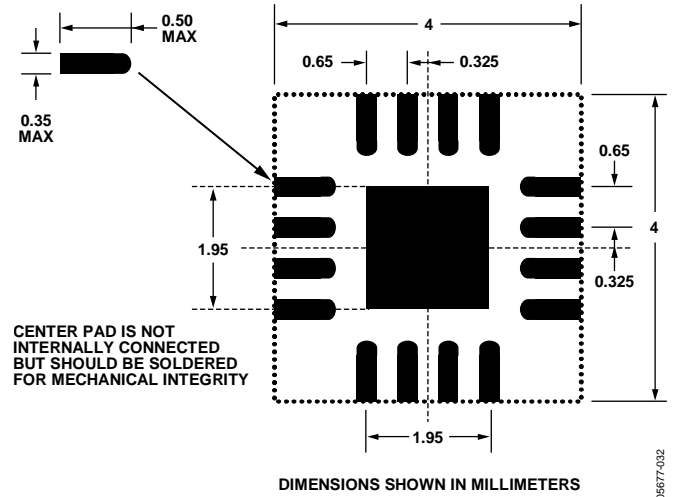


Figure 4. Recommended PCB Layout

Table 4. Pin Function Descriptions

Pin No.	Mnemonic	Description
1	NC	No Connect (or optionally ground)
2	ST	Self Test
3	NC	No Connect <sup>1</sup>
4	NC	No Connect <sup>1</sup>
5	COM	Common
6	NC	No Connect <sup>1</sup>
7	NC	No Connect <sup>1</sup>
8	Z <sub>OUT</sub>	Z Channel Output
9	NC	No Connect (or optionally ground)
10	Y <sub>OUT</sub>	Y Channel Output
11	NC	No Connect <sup>1</sup>
12	X <sub>OUT</sub>	X Channel Output
13	NC	No Connect <sup>1</sup>
14	NC	No Connect <sup>1</sup>
15	V <sub>s</sub>	Supply Voltage (1.8 V to 3.6 V)
16	NC	No Connect <sup>1</sup>

<sup>1</sup>NC pins are not internally connected and can be tied to V<sub>s</sub> or Common unless otherwise noted.

## THEORY OF OPERATION

The ADXL335 is a complete 3-axis acceleration measurement system. The ADXL335 has a measurement range of  $\pm 3$  g minimum. It contains a polysilicon surface micromachined sensor and signal conditioning circuitry to implement an open-loop acceleration measurement architecture. The output signals are analog voltages that are proportional to acceleration. The accelerometer can measure the static acceleration of gravity in tilt sensing applications as well as dynamic acceleration resulting from motion, shock, or vibration.

The sensor is a polysilicon surface micromachined structure built on top of a silicon wafer. Polysilicon springs suspend the structure over the surface of the wafer and provide a resistance against acceleration forces. Deflection of the structure is measured using a differential capacitor that consists of independent fixed plates and plates attached to the moving mass. The fixed plates are driven by  $180^\circ$  out-of-phase square waves. Acceleration deflects the moving mass and unbalances the differential capacitor resulting in a sensor output whose amplitude is proportional to acceleration. Phase-sensitive demodulation techniques are then used to determine the magnitude and direction of the acceleration.

The demodulator output is amplified and brought off-chip through a  $32\text{ k}\Omega$  resistor. The user then sets the signal bandwidth of the device by adding a capacitor. This filtering improves measurement resolution and helps prevent aliasing.

## MECHANICAL SENSOR

The ADXL335 uses a single structure for sensing the X, Y, and Z axes. As a result, the three axes sense directions are highly orthogonal with little cross axis sensitivity. Mechanical misalignment of the sensor die to the package is the chief source of cross axis sensitivity. Mechanical misalignment can, of course, be calibrated out at the system level.

## PERFORMANCE

Rather than using additional temperature compensation circuitry, innovative design techniques ensure high performance is built-in to the ADXL335. As a result, there is neither quantization error nor nonmonotonic behavior, and temperature hysteresis is very low (typically less than 3 mg over the  $-25^\circ\text{C}$  to  $+70^\circ\text{C}$  temperature range).

## APPLICATIONS

### POWER SUPPLY DECOUPLING

For most applications, a single 0.1 μF capacitor, C<sub>DC</sub>, placed close to the ADXL335 supply pins adequately decouples the accelerometer from noise on the power supply. However, in applications where noise is present at the 50 kHz internal clock frequency (or any harmonic thereof), additional care in power supply bypassing is required as this noise can cause errors in acceleration measurement. If additional decoupling is needed, a 100 Ω (or smaller) resistor or ferrite bead can be inserted in the supply line. Additionally, a larger bulk bypass capacitor (1 μF or greater) can be added in parallel to C<sub>DC</sub>. Ensure that the connection from the ADXL335 ground to the power supply ground is low impedance because noise transmitted through ground has a similar effect as noise transmitted through V<sub>S</sub>.

### SETTING THE BANDWIDTH USING C<sub>X</sub>, C<sub>Y</sub>, AND C<sub>Z</sub>

The ADXL335 has provisions for band limiting the X<sub>OUT</sub>, Y<sub>OUT</sub>, and Z<sub>OUT</sub> pins. Capacitors must be added at these pins to implement low-pass filtering for antialiasing and noise reduction. The equation for the 3 dB bandwidth is

$$F_{-3\text{ dB}} = 1/(2\pi(32\text{ k}\Omega) \times C_{(X, Y, Z)})$$

or more simply

$$F_{-3\text{ dB}} = 5\ \mu\text{F}/C_{(X, Y, Z)}$$

The tolerance of the internal resistor (R<sub>FILT</sub>) typically varies as much as ±15% of its nominal value (32 kΩ), and the bandwidth varies accordingly. A minimum capacitance of 0.0047 μF for C<sub>X</sub>, C<sub>Y</sub>, and C<sub>Z</sub> is recommended in all cases.

**Table 5. Filter Capacitor Selection, C<sub>X</sub>, C<sub>Y</sub>, and C<sub>Z</sub>**

Bandwidth (Hz)	Capacitor (μF)
1	4.7
10	0.47
50	0.10
100	0.05
200	0.027
500	0.01

### SELF TEST

The ST pin controls the self test feature. When this pin is set to V<sub>S</sub>, an electrostatic force is exerted on the accelerometer beam. The resulting movement of the beam allows the user to test if the accelerometer is functional. The typical change in output is –500 mg (corresponding to –150 mV) in the X-axis, 500 mg (or 150 mV) on the Y-axis, and –200 mg (or –60 mV) on the Z-axis. This ST pin may be left open circuit or connected to common (COM) in normal use.

Never expose the ST pin to voltages greater than V<sub>S</sub> + 0.3 V. If this cannot be guaranteed due to the system design (for instance, if there are multiple supply voltages), then a low V<sub>F</sub> clamping diode between ST and V<sub>S</sub> is recommended.

### DESIGN TRADE-OFFS FOR SELECTING FILTER CHARACTERISTICS: THE NOISE/BW TRADE-OFF

The selected accelerometer bandwidth ultimately determines the measurement resolution (smallest detectable acceleration). Filtering can be used to lower the noise floor to improve the resolution of the accelerometer. Resolution is dependent on the analog filter bandwidth at X<sub>OUT</sub>, Y<sub>OUT</sub>, and Z<sub>OUT</sub>.

The output of the ADXL335 has a typical bandwidth of greater than 500 Hz. The user must filter the signal at this point to limit aliasing errors. The analog bandwidth must be no more than half the analog-to-digital sampling frequency to minimize aliasing. The analog bandwidth can be further decreased to reduce noise and improve resolution.

The ADXL335 noise has the characteristics of white Gaussian noise, which contributes equally at all frequencies and is described in terms of μg/√Hz (the noise is proportional to the square root of the accelerometer bandwidth). The user should limit bandwidth to the lowest frequency needed by the application to maximize the resolution and dynamic range of the accelerometer.

With the single-pole, roll-off characteristic, the typical noise of the ADXL335 is determined by

$$rms\ Noise = Noise\ Density \times (\sqrt{BW} \times 1.6)$$

Often, the peak value of the noise is desired. Peak-to-peak noise can only be estimated by statistical methods. Table 6 is useful for estimating the probabilities of exceeding various peak values, given the rms value.

**Table 6. Estimation of Peak-to-Peak Noise**

Peak-to-Peak Value	% of Time that Noise Exceeds Nominal Peak-to-Peak Value
2 × rms	32
4 × rms	4.6
6 × rms	0.27
8 × rms	0.006

### USE WITH OPERATING VOLTAGES OTHER THAN 3 V

The ADXL335 is tested and specified at V<sub>S</sub> = 3 V; however, it can be powered with V<sub>S</sub> as low as 1.8 V or as high as 3.6 V. Note that some performance parameters change as the supply voltage is varied.

The ADXL335 output is ratiometric, therefore, the output sensitivity (or scale factor) varies proportionally to the supply voltage. At  $V_s = 3.6\text{ V}$ , the output sensitivity is typically  $360\text{ mV/g}$ . At  $V_s = 2\text{ V}$ , the output sensitivity is typically  $195\text{ mV/g}$ .

The zero  $g$  bias output is also ratiometric, so the zero  $g$  output is nominally equal to  $V_s/2$  at all supply voltages.

The output noise is not ratiometric but is absolute in volts; therefore, the noise density decreases as the supply voltage increases. This is because the scale factor ( $\text{mV/g}$ ) increases while the noise voltage remains constant. At  $V_s = 3.6\text{ V}$ , the X- and Y-axis noise density is typically  $120\text{ }\mu\text{g}/\sqrt{\text{Hz}}$ , while at  $V_s = 2\text{ V}$ , the X- and Y-axis noise density is typically  $270\text{ }\mu\text{g}/\sqrt{\text{Hz}}$ .

Self test response in  $g$  is roughly proportional to the square of the supply voltage. However, when ratiometricity of sensitivity is factored in with supply voltage, the self test response in volts is roughly proportional to the cube of the supply voltage. For example, at  $V_s = 3.6\text{ V}$ , the self test response for the ADXL335 is approximately  $-275\text{ mV}$  for the X-axis,  $+275\text{ mV}$  for the Y-axis, and  $-100\text{ mV}$  for the Z-axis.

At  $V_s = 2\text{ V}$ , the self test response is approximately  $-60\text{ mV}$  for the X-axis,  $+60\text{ mV}$  for the Y-axis, and  $-25\text{ mV}$  for the Z-axis.

The supply current decreases as the supply voltage decreases. Typical current consumption at  $V_s = 3.6\text{ V}$  is  $375\text{ }\mu\text{A}$ , and typical current consumption at  $V_s = 2\text{ V}$  is  $200\text{ }\mu\text{A}$ .

**AXES OF ACCELERATION SENSITIVITY**

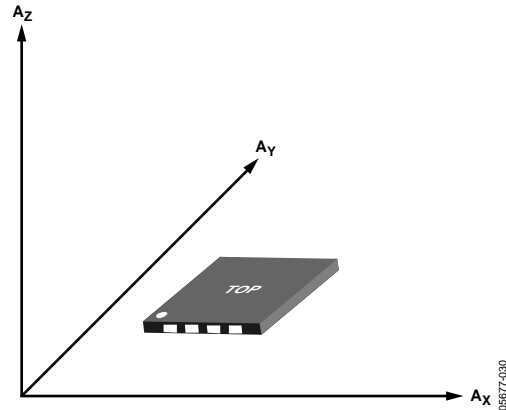


Figure 5. Axes of Acceleration Sensitivity, Corresponding Output Voltage Increases When Accelerated Along the Sensitive Axis

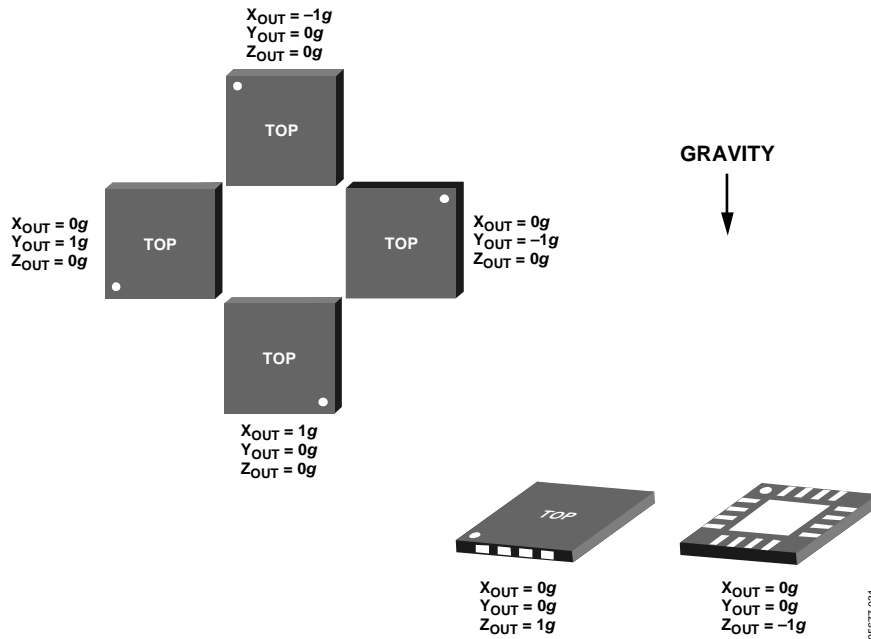
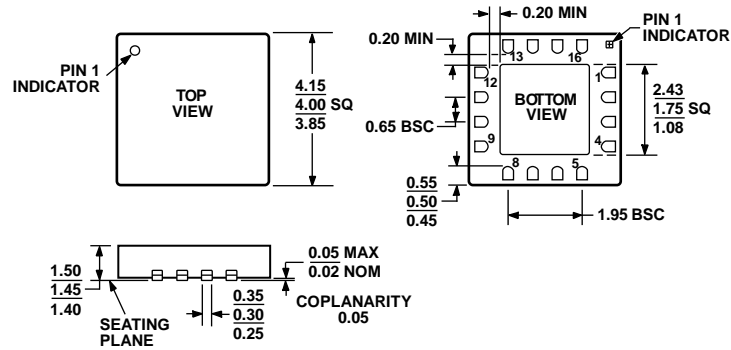


Figure 6. Output Response vs. Orientation to Gravity



### OUTLINE DIMENSIONS



\*STACKED DIE WITH GLASS SEAL.

Figure 7. 16-Lead Lead Frame Chip Scale Package [LFCSP\_LQ]  
 4 mm × 4 mm Body, 1.45mm Thick Quad  
 (CP-16-5a\*)  
 Dimensions shown in millimeters

072606-A

### ORDERING GUIDE

Model	Measurement Range	Specified Voltage	Temperature Range	Package Description	Package Option
ADXL335BCPZ <sup>1</sup>	±3 g	3 V	-40°C to +85°C	16-Lead LFCSP_LQ	CP-16-5a
ADXL335BCPZ-RL <sup>1</sup>	±3 g	3 V	-40°C to +85°C	16-Lead LFCSP_LQ	CP-16-5a
ADXL335BCPZ-RL7 <sup>1</sup>	±3 g	3 V	-40°C to +85°C	16-Lead LFCSP_LQ	CP-16-5a
EVAL-ADXL335Z <sup>1</sup>				Evaluation Board	

<sup>1</sup> Z = Pb-free part.

**NOTES**

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